Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/611,501	STERRETT ET AL.
Examiner	Art Unit
Chris C. Chu	2815

	SEARCHED				
Class	Subclass	Date	Examiner		
257	777 & 686	3/28/2005	C.C.		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	_			

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
Searched in US-PGPUB; USPAT; EPO; JPO; DERWENT; and IBM_TDB;	3/28/2005	c.c.